

## HAF1002(L), HAF1002(S)

# Silicon P Channel MOS FET Series Power Switching

REJ03G1133-0200

(Previous: ADE-208-586)

Rev.2.00 Sep 07, 2005

## **Description**

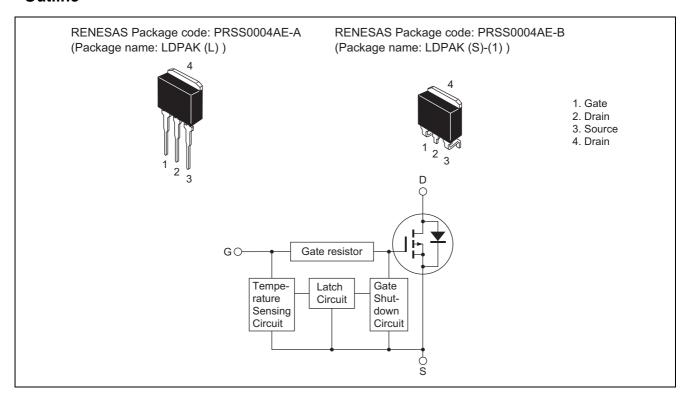
This FET has the over temperature shut-down capability sensing to the junction temperature.

This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

#### **Features**

- Logic level operation (–4 to –6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut-down operation (Need 0 voltage recovery)

### **Outline**



## **Absolute Maximum Ratings**

 $(Ta = 25^{\circ}C)$ 

Item	Symbol	Value	Unit
Drain to source voltage	V <sub>DSS</sub>	-60	V
Gate to source voltage	V <sub>GSS</sub>	-16	V
	V <sub>GSS</sub>	3	V
Drain current	I <sub>D</sub>	-15	Α
Drain peak current	I <sub>D (pulse)</sub> Note 1	-30	A
Body-drain diode reverse drain current	I <sub>DR</sub>	-15	A
Channel dissipation	Pch Note 2	50	W
Channel temperature	Tch	150	°C
Storage temperature	Tstg	-55 to +150	°C

Notes: 1. PW  $\leq$  10  $\mu$ s, duty cycle  $\leq$  1%

2. Value at  $Tc = 25^{\circ}C$ 

## **Typical Operation Characteristics**

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Input voltage	V <sub>IH</sub>	-3.5	_	_	V	
	V <sub>IL</sub>	_	_	-1.2	V	
Input current	I <sub>IH1</sub>	_	_	-100	μΑ	$Vi = -8 V, V_{DS} = 0$
(Gate non shut down)	I <sub>IH2</sub>	_	_	-50	μΑ	$Vi = -3.5 \text{ V}, V_{DS} = 0$
	I <sub>IL</sub>	_	_	-1	μΑ	$Vi = -1.2 V, V_{DS} = 0$
Input current	I <sub>IH (sd) 1</sub>	_	-0.8	_	mA	$Vi = -8 V, V_{DS} = 0$
(Gate shut down)	I <sub>IH (sd) 2</sub>	_	-0.35	_	mA	$Vi = -3.5 \text{ V}, V_{DS} = 0$
Shut down temperature	Tsd	_	175	_	°C	Channel temperature
Gate operation voltage	V <sub>OP</sub>	-3.5	_	-13	V	

## **Electrical Characteristics**

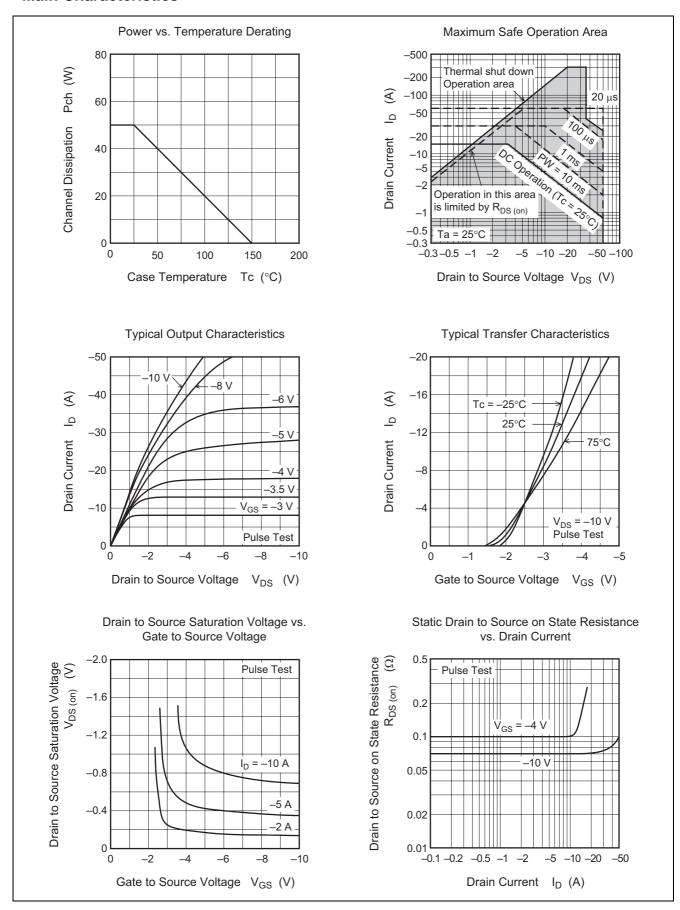
 $(Ta = 25^{\circ}C)$ 

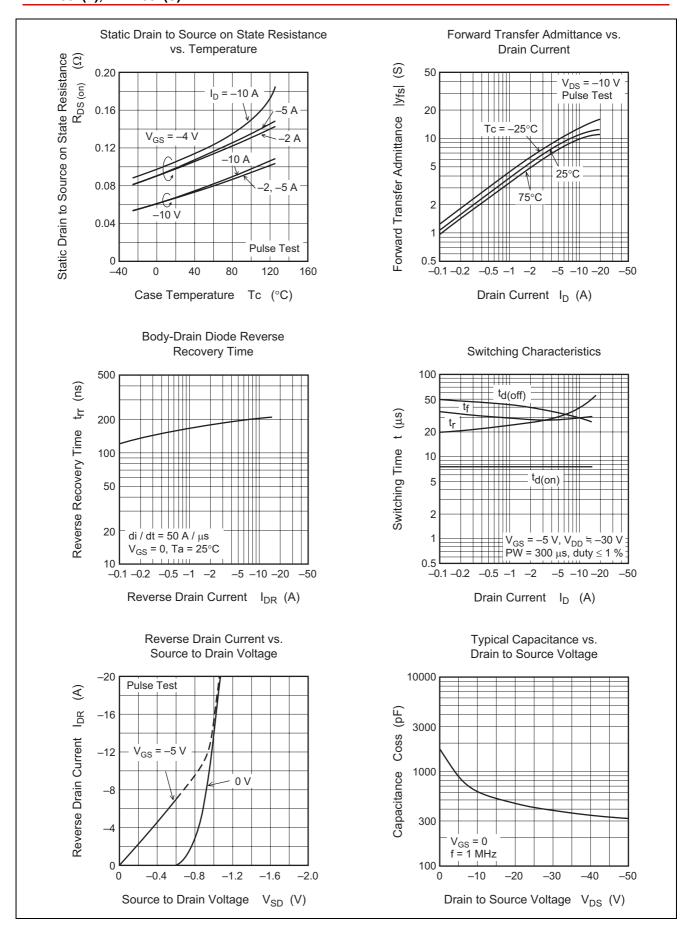
Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain current	I <sub>D1</sub>	-7	_	_	Α	$V_{GS} = -3.5 \text{ V}, V_{DS} = -2 \text{ V}$
	I <sub>D2</sub>	_	_	-10	mA	$V_{GS} = -1.2 \text{ V}, V_{DS} = -2 \text{ V}$
Drain to source breakdown voltage	V <sub>(BR) DSS</sub>	-60	_	_	V	$I_D = -10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	V <sub>(BR) GSS</sub>	-16	_	_	V	$I_G = -100 \mu A, V_{DS} = 0$
	V <sub>(BR)</sub> GSS	3	—	_	V	$I_G = 100  \mu A,  V_{DS} = 0$
Gate to source leak current	I <sub>GSS1</sub>			-100	μΑ	$V_{GS} = -8 \text{ V}, V_{DS} = 0$
	I <sub>GSS2</sub>			-50	μΑ	$V_{GS} = -3.5 \text{ V}, V_{DS} = 0$
	I <sub>GSS3</sub>			-1	μΑ	$V_{GS} = -1.2 \text{ V}, V_{DS} = 0$
	I <sub>GSS4</sub>			100	μΑ	$V_{GS} = 2.4 \text{ V}, V_{DS} = 0$
Input current (shut down)	I <sub>GS (op) 1</sub>		-0.8	_	mA	$V_{GS} = -8 \text{ V}, V_{DS} = 0$
	I <sub>GS (op) 2</sub>		-0.35	_	mA	$V_{GS} = -3.5 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>			-250	μΑ	$V_{DS} = -50 \text{ V}, V_{GS} = 0$
Gate to source cutoff voltage	V <sub>GS (off)</sub>	-1.1		-2.25	>	$I_D = -1 \text{ mA}, V_{DS} = -10 \text{ V}$
Static drain to source on state resistance	R <sub>DS (on)</sub>		100	130	mΩ	$I_D = -7.5 \text{ A}, V_{GS} = -4 \text{ V}^{\text{Note 3}}$
	R <sub>DS (on)</sub>	—	70	90	mΩ	$I_D = -7.5 \text{ A}, V_{GS} = -10 \text{ V}^{\text{Note 3}}$
Forward transfer admittance	y <sub>fs</sub>	5	10	—	S	$I_D = -7.5 \text{ A}, V_{DS} = -10 \text{ V}^{\text{Note 3}}$
Output capacitance	Coss	_	610	_	pF	$V_{DS} = -10 \text{ V}, V_{GS} = 0$
						f = 1 MHz
Turn-on delay time	t <sub>d (on)</sub>	—	7.5	_	μs	$I_D = -7.5 \text{ A}$
Rise time	t <sub>r</sub>	—	36	_	μs	$V_{GS} = -5 \text{ V}$
Turn-off delay time	t <sub>d (off)</sub>	—	32	_	μs	$R_L = 4 \Omega$
Fall time	t <sub>f</sub>		29	_	μs	
Body-drain diode forward voltage	$V_{DF}$		-1.0	_	>	$I_F = -15 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	t <sub>rr</sub>		200	_	ns	$I_F = -15 \text{ A}, V_{GS} = 0$
						di <sub>F</sub> /dt = 50 A/μs
Over load shut down operation time Note4	t <sub>os1</sub>		3.7	_	ms	$V_{GS} = -5 \text{ V}, V_{DD} = -12 \text{ V}$
	t <sub>os2</sub>	_	1	_	ms	$V_{GS} = -5 \text{ V}, V_{DD} = -24 \text{ V}$

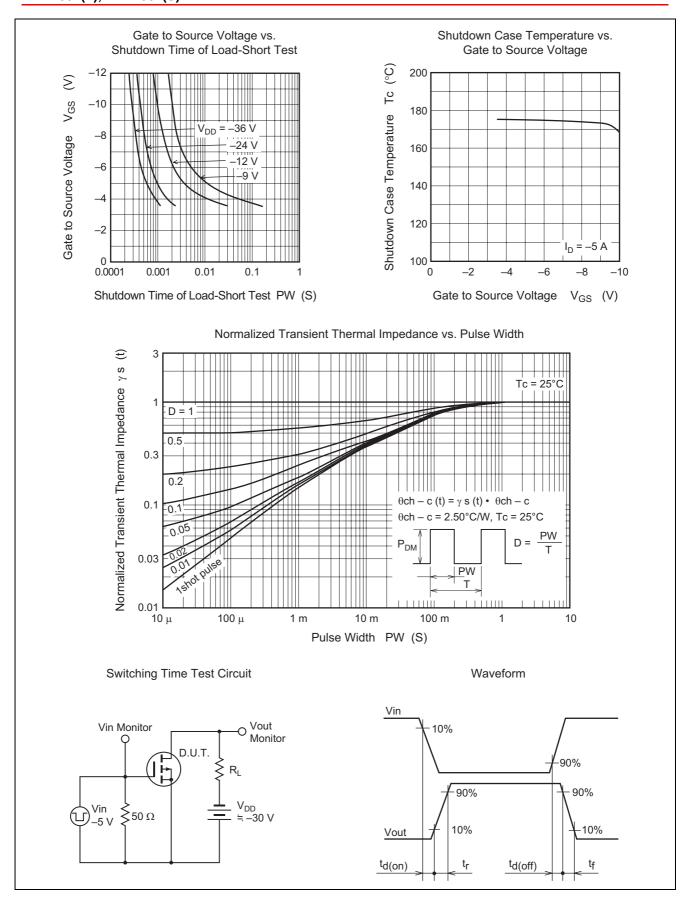
Notes: 3. Pulse test

4. Include the time shift based on increasing of channel temperature when operate under over load condition.

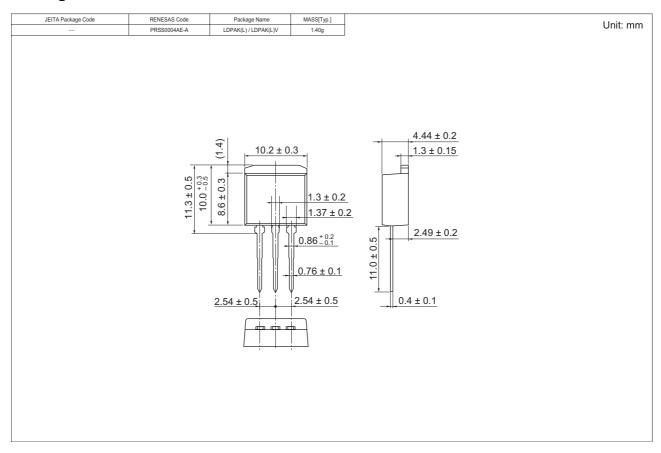
### **Main Characteristics**

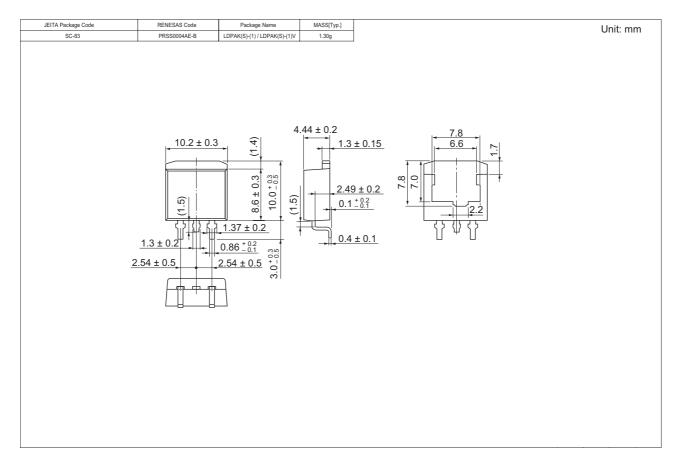






## **Package Dimensions**





## **Ordering Information**

Part Name	Quantity	Shipping Container
HAF1002-90L	Max: 50 pcs/sack	Sack
HAF1002-90S	Max: 50 pcs/sack	Sack
HAF1002-90STL	1000 pcs/Reel	Embossed tape
HAF1002-90STR	1000 pcs/Reel	Embossed tape

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